## Notice of References Cited

2		
Application/Control No.	Applicant(s)/Pate	nt Under
10/018,085	Reexamination WERMEISTER E	T AL.
Examiner	Art Unit	
Brian D. Walsh	3722	Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,032,049	07-1991	Hessman et al.	407/113
_	В	US-5,924,826 A	07-1999	Bystrom et al.	407/103
-	С	US-3,701,187 /	10-1972	Erkfritz, Donald S.	407/46
	D	US-2002/0098360 A1	07-2002	OKAMURA et al.	428/408
	E	US-4,056,872	11-1977	Seidel, Heinz H.	407/114
	F	US-5,944,456 A	08-1999	Shirley et al.	407/42
	G	US-6,168,356 B1 -	01-2001	Sjoo et al.	407/104
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 7060509 V	03-1995	JP	Matsumoto et al.	
	0					
	Р			1		
	Q					
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	w					
	х					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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